Issue Classification

Application/Control No.	Applicant(s)/Patent Under Reexamination
10033210	SHIMIZU, SEIYA
Examiner	**Art Unit**
RICHARD M BEMBEN	2622

ORIGINAL		INTERNATIONAL CLASSIFICATION	
CLASS	SUBCLASS	CLAIMED	NON-CLAIMED
725	105	H 0 4 N 7 / 173 (2006.01.01)	
CROSS REFERENCE(S)		H 0 4 N 5 / 225 (2006.01.01)	
		H 0 4 N 9 / 04 (2006.01.01)	
CLASS	SUBCLASS (ONE SUBCLASS PER BLOCK)	H 0 4 N 5 / 232 (2006.01.01)	
348	207.1 207.99 211.1 211.3		

/RICHARD M BEMBEN/ (Assistant Examiner)	3/17/08 (Date)	**Total Claims Allowed:** 5	
/Lin Ye/ (Primary Examiner)	3/17/08 (Date)	O.G. Print Claim(s) 1	O.G. Print Figure 3